

## N-Channel 100 V (D-S) 175 °C MOSFET

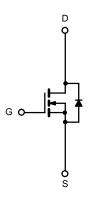
PRODUCT SUMMARY				
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A)		
100	0.004 at V <sub>GS</sub> = 10 V	140 <sup>a</sup>		

#### **FEATURES**

- TrenchFET<sup>®</sup> Power MOSFET
- New Package with Low Thermal Resistance
- 100 % R<sub>g</sub> Tested







N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> $T_{C} = 25 \text{ °C}$ , unless otherwise noted					
Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V <sub>DS</sub>	100	N/		
Gate-Source Voltage	V <sub>GS</sub>	± 20	V		
Continuous Drain Current (T <sub>J</sub> = 175 °C)	T <sub>C</sub> = 25 °C		140 <sup>a</sup>	^	
	T <sub>C</sub> = 125 °C		87 <sup>a</sup>		
Pulsed Drain Current	I <sub>DM</sub>	440	A		
Avalanche Current	I <sub>AR</sub>	75			
Repetitive Avalanche Energy <sup>b</sup>	L = 0.1 mH	E <sub>AR</sub>	280	mJ	
Maximum Power Dissipation <sup>b</sup>	T <sub>C</sub> = 25 °C	Р	375 <sup>c</sup>	W	
	T <sub>A</sub> = 25 °C	P <sub>D</sub>	3.75		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Limit	Unit	
Junction-to-Ambient	R <sub>thJA</sub>	40	°C/W		
Junction-to-Case (Drain)		R <sub>thJC</sub>	0.4	0/10	

Notes:

a. Package limited.

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b. Duty cycle ≤ 1 %.
c. See SOA curve for voltage derating.
d. When mounted on 1" square PCB (FR-4 material).

<b>SPECIFICATIONS</b> T <sub>J</sub> = 25 °C, unless otherwise noted						
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static		-				
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{DS} = 0 \text{ V}, \text{ I}_{D} = 250 \mu\text{A}$	100			v
Gate-Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$	2		4	
Gate-Body Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
		$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS}$ = 100 V, $V_{GS}$ = 0 V, $T_{J}$ = 125 °C			50	
		$V_{DS}$ = 100 V, $V_{GS}$ = 0 V, $T_{J}$ = 175 °C			250	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 V$ , $V_{GS} = 10 V$	120			A
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 30 A		0.004		
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 30 A, T <sub>J</sub> = 125 °C		0.017		Ω
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 30 A, T <sub>J</sub> = 175 °C		0.025		
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 30 A	25			S
Dynamic <sup>b</sup>	-					
Input Capacitance	C <sub>iss</sub>			5500		pF
Output Capacitance	C <sub>oss</sub>	$V_{GS}$ = 0 V, $V_{DS}$ = 25 V, f = 1 MHz		750		
Reverse Transfer Capacitance	C <sub>rss</sub>			280		
Total Gate Charge <sup>c</sup>	Qg			110	160	nC
Gate-Source Charge <sup>c</sup>	Q <sub>gs</sub>	$V_{DS} = 50 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 85 \text{ A}$		24		
Gate-Drain Charge <sup>c</sup>	Q <sub>gd</sub>			24		
Gate Resistance	Rg		1.0		6.2	Ω
Turn-On Delay Time <sup>c</sup>	t <sub>d(on)</sub>			20	30	
Rise Time <sup>c</sup>	t <sub>r</sub>	$V_{DD} = 50 \text{ V}, \text{ R}_{1} = 0.6 \Omega$		125	200	ns
Turn-Off Delay Time <sup>c</sup>	t <sub>d(off)</sub>	$I_D \cong 85$ Å, $V_{GEN}$ = 10 V, $R_g$ = 2.5 $\Omega$		55	85	
Fall Time <sup>c</sup>	t <sub>f</sub>			130	195	
Source-Drain Diode Ratings and Characteristics $T_c = 25 \text{ °C}^b$						
Continuous Current	۱ <sub>S</sub>				140	A
Pulsed Current	I <sub>SM</sub>				240	
Forward Voltage <sup>a</sup>	V <sub>SD</sub>	I <sub>F</sub> = 85 A, V <sub>GS</sub> = 0 V		1.0	1.5	V
Reverse Recovery Time	t <sub>rr</sub>			70	140	ns
Peak Reverse Recovery Charge	I <sub>RM(REC)</sub>	I <sub>F</sub> = 50 A, dl/dt = 100 A/μs		5.5	10	А
Reverse Recovery Charge	Q <sub>rr</sub>			0.19	0.35	μC

Notes:

a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %.

b. Guaranteed by design, not subject to production testing.

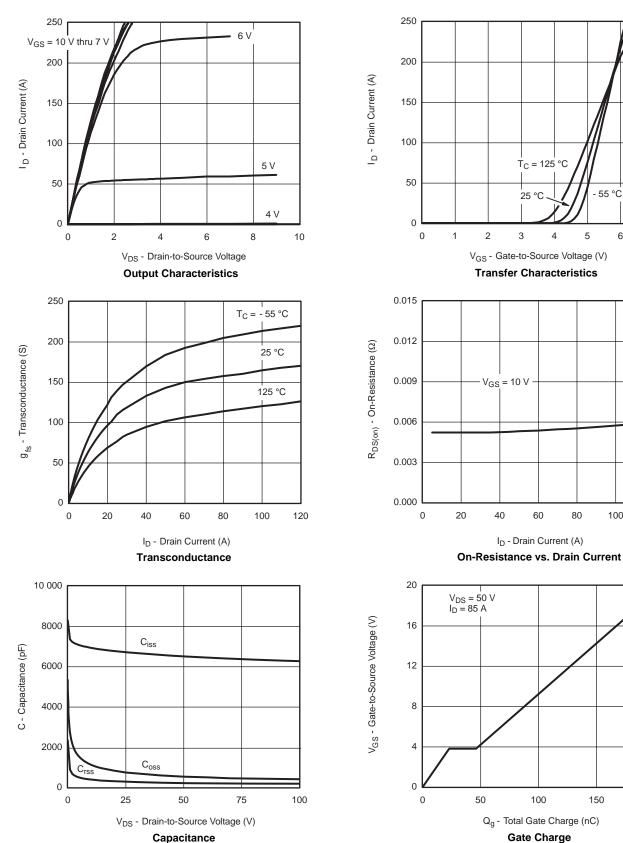
c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

emi

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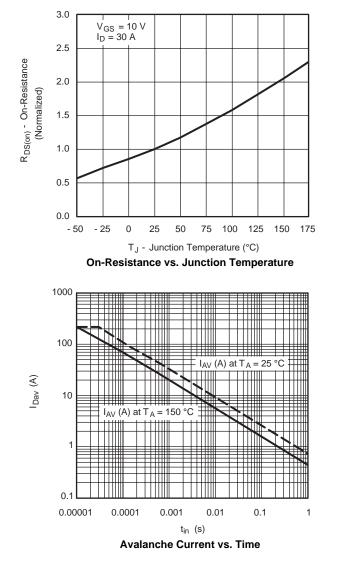


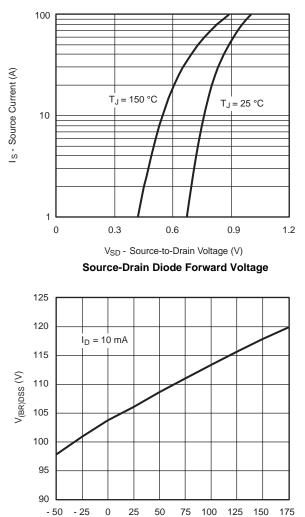


#### TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



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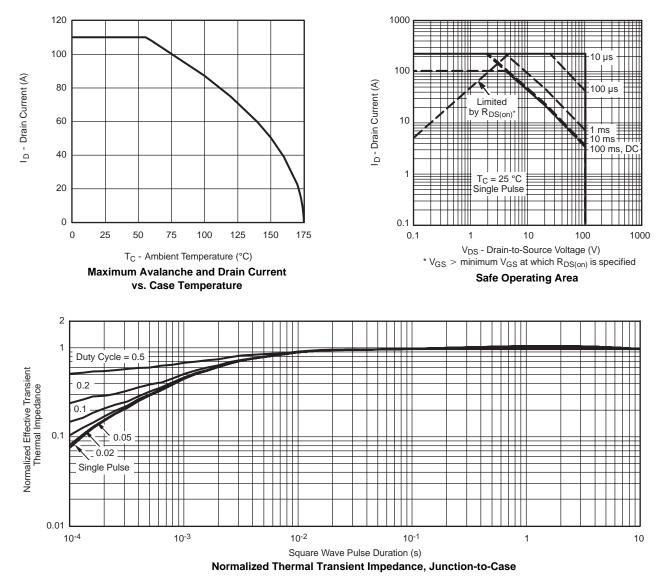


T<sub>J</sub> - Junction Temperature (°C) Drain Source Breakdown vs. Junction Temperature

### **PSMN3R8-100BS**

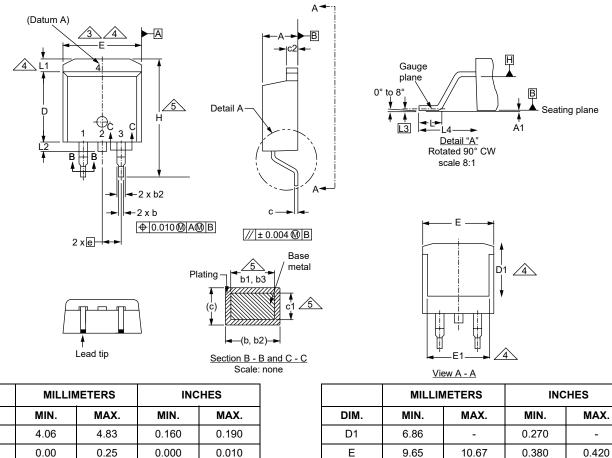


#### **THERMAL RATINGS**





#### **TO-263AB (HIGH VOLTAGE)**



Е

E1

е

Н

L

L1

L2

L3

L4

9.65

6.22

14.61

1.78

-

4.78

10.67

-

15.88

2.79

1.65

1.78

5.28

2.54 BSC

0.25 BSC

0.380

0.245

0.575

0.070

-

0.188

0.100 BSC

0.010 BSC

-

0.625

0.110

0.066

0.070

0.208

D	8.38	9.65			
ECN: S-82110-Rev. A, 15-Sep-08					

0.51

0.51

1.14

1.14

0.38

0.38

1.14

DWG: 5970

Notes

DIM.

А

A1

b

b1

b2

b3

С

c1

c2

1. Dimensioning and tolerancing per ASME Y14.5M-2018.

0.99

0.89

1.78

1.73

0.74

0.58

1.65

0.020

0.020

0.045

0.045

0.015

0.015

0.045

0.330

0.039

0.035

0.070

0.068

0.029

0.023

0.065

0.380

2. Dimensions are shown in millimeters (inches).

3. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm (0.005") per side. These dimensions are measured at the outmost extremes of the plastic body at datum A.

4. Thermal PAD contour optional within dimension E, L1, D1 and E1.

5. Dimension b1 and c1 apply to base metal only.

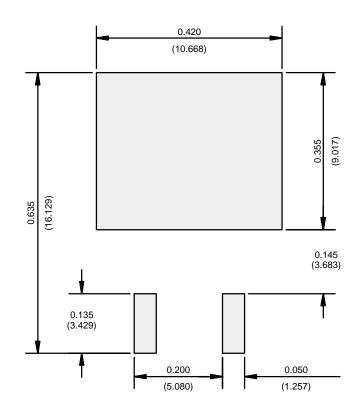
6. Datum A and B to be determined at datum plane H.

7. Outline conforms to JEDEC outline to TO-263AB.

## PSMN3R8-100BS



#### **RECOMMENDED MINIMUM PADS FOR D<sup>2</sup>PAK: 3-Lead**



Recommended Minimum Pads Dimensions in Inches/(mm)



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